

5.0kV_{RMS} Opto-Compatible Single Channel Isolated Gate Driver

GENERAL DESCRIPTION

The SLM34x isolated driver family is an optocompatible, single channel, isolated MOSFET, IGBT gate driver with different drive current capability and UVLO voltage level. The peak output currents are from 1.0A to 4.0A. Key features and characteristics bring significant performance and reliability upgrades over standard opto-coupler based gate drivers while maintaining pin-to-pin compatibility in both schematic and layout design. Performance highlights include high common mode transient immunity (CMTI), low propagation delay, and small pulse width distortion.

The input stage is an emulated diode which means long term reliability and excellent aging characteristics compared to traditional LEDs. It is offered in a SOP6W package with ≥8.0mm creepage and clearance. A mold compound from material group II which has a comparative tracking index (CTI) >400V. High performance and reliability of the SLM34x makes it ideal for use in all types of motor drives, solar inverters, industrial power supplies, and appliances.

APPLICATION

- AC and brushless DC motor drives
- Renewable energy inverters
- Industrial power supplies

FEATURES

- 1.0A to 4.0A peak output current
- 120ns (Max.) propagation delay
- 25ns (Max.) part-to-part delay matching
- 35ns (Max.) pulse width distortion
- 150kV/us (Min.) common mode transient immunity (CMTI)
- Wide gate drive supply voltage
 - 10 V to 40 V for SLM345/6
 - 14 V to 40 V for SLM340/1/3
- 30V reverse polarity voltage handling capability on input stage
- Pin to pin compatible to opto-coupler isolated gate drivers
- SOP6W package with ≥8.0mm creepage and clearance
- Junction temperature, T_J: -40°C to +150°C
- Safety certifications
 - 5kVRMs isolation for 1 minute per UL 1577
 - CQC certification per GB4943.1-2011
 - DIN VDE 0884-17: 2021-10

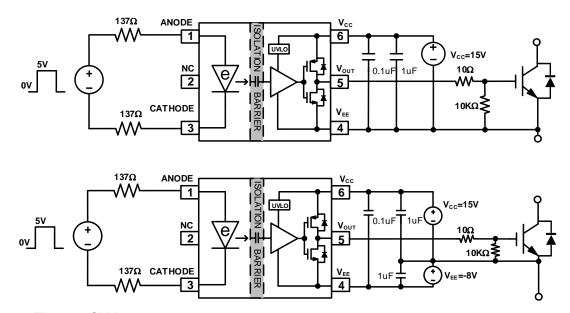


Figure 1. SLM34x Single and Bipolar Power Supplies Application Circuit to Drive IGBT



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PIN CONFIGURATION

Package	Pin Configuration (Top View)
SOP6W	ANODE 1 0 6 V _{CC} NC 2 5 V _{OUT} CATHODE 1 V _{EE}

PIN DESCRIPTION

No.	Pin	Description
1	ANODE	Anode
2	NC	No Connection
3	CATHODE	Cathode
4	VEE	Negative Power Supply Rail
5	Vouт	Gate Drive Output
6	Vcc	Positive Power Supply Rail

FUNCTIONAL BLOCK DIAGRAM

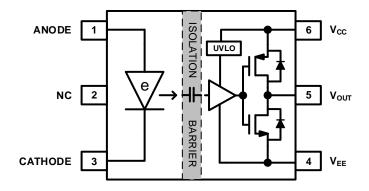


Figure 2. SLM34x Functional Block Diagram



ORDERING INFORMATION

Order Part No.	Package	QTY
SLM340CK-DG	SOP6W, Pb-Free	1000/Reel
SLM341CK-DG	SOP6W, Pb-Free	1000/Reel
SLM343CK-DG	SOP6W, Pb-Free	1000/Reel
SLM345CK-DG	SOP6W, Pb-Free	1000/Reel
SLM346CK-DG	SOP6W, Pb-Free	1000/Reel

FAMILY OVERIEW

Part Number	Peak Output Current	UVLO	Isolation Rating
SLM340	1.0 A	12.5V	5.0kVrms
SLM341	3.0 A	12.5V	5.0kVrms
SLM343	4.0 A	12.5V	5.0kVrms
SLM345	1.0 A	8.5V	5.0kVrms
SLM346	3.0 A	8.5V	5.0kVrms



ABSOLUTE MAXIMUM RATINGS

Symbol	Definition	Min	Max	Unit
I _{F(AVG)}	I _{F(AVG)} Average Input Current		25	mA
V_R	Reverse Input Voltage		30	V
V _{CC} -V _{EE}	Output supply voltage		45	V
TJ	Junction temperature	-40	150	°C
Ts	Storage temperature	-55	150	

RECOMMENDED OPERTION CONDITIONS

Symbol	Definition	Min	Max	Unit
Vcc -Vee	Output Supply Voltage (SLM340/SLM341/ SLM343)	14	40	V
ACC - AEE	Output Supply Voltage (SLM345/SLM346)	10	40	V
I _F (ON)	Input Diode Forward Current (Diode "ON")	7	16	mA
V _F (OFF)	Anode Voltage - Cathode Voltage (Diode "OFF")	-30	0.9	V
TJ	Junction temperature	-40	150	°C
TA	Ambient temperature	-40	125	°C

ESD RATINGS

Symbol	Definition	Value	Unit
Vesd	НВМ	±4000	V
VESD	CDM	±2000	v

THERMAL INFORMATION

Symbol	Definition	Value	Unit
R _θ JA	Junction to ambient thermal resistance	125	°C/W
Rejc	Junction to case (top) thermal resistance	66	°C/W
Ψл	Junction to top characterization parameter	30	°C/W



PACKAGE SPECIFICATIONS

Symbol	Definition	Min	Тур	Max	Units
R _{IO}	Resistance (Input Side to Output Side)		10 ¹²		Ω
C _{IO}	Capacitance (Input Side to Output Side)		0.8		pF
C _{IN}	Input Capacitance		30		pF

INSULATION SPECIFICATIONS

Symbol	Definition	Test Condition	Value	Units
CLR	External clearance	Shortest terminal to terminal distance through air	≥8	mm
CPG	External creepage	Shortest terminal to terminal distance across the package surface	≥8	mm
DTI	Distance through the insulation	Minimum internal gap	>16	um
СТІ	Comparative tracking index	DIN EN 60112 (VDE 0303-11), IEC 60112	>400	V
	Material Group		II	
		Rated mains voltages ≤150Vrms	IV	
		Rated mains voltages ≤300Vrms	IV	
	Overvoltage category	Rated mains voltages ≤600Vrms	III	
		Rated mains voltages ≤1000Vrms	П	
DIN V VDE	0884-11			- 1
Viorm	Maximum repetitive peak isolation voltage		1414	V _{PK}
Viowm	Maximum isolation working voltage		1000	V _{RMS}
V _{IOTM}	Maximum transient isolation voltage	60s	7000	V_{PK}
Viosm	Maximum surge isolation voltage	Test method per IEC62368, 1.2/50us waveform, V _{TEST} =1.6 x V _{IOSM}	6250	V _{PK}
q pd	Apparent charge	Method b2: $V_{pd(m)}$ =1.875 x V_{IORM} , tm=1 s	≤5	pC
	Climatic Category		40/125/21	
	Pollution Degree		2	
UL1577	1			ı
V _{ISO}	Withstand Isolation Voltage	V _{TEST} =V _{ISO} , t=60s (qualification), V _{TEST} =1.2 x V _{ISO} , t=1s (100% production)	5000	V _{RMS}



SAFETY RELATED CERTIFICATIONS

VDE	UL	CQC
DIN VDE 0884-17: 2021-10	UL 1577 component recognition	Certified according to
	program	GB4943.1-2011
Reinforced Insulation	Single protection, 5000 V _{RMS}	Reinforced insulation,
VIORM = 1414 VPK		Altitude ≤ 5000m, Tropical climate, 400 V _{RMS} maximum working voltage
VIOTM = 7000 VPK		THE
V _{IOSM} = 6250 V _{PK}		
Certification number: 40055782	File number: E521801	File number: CQC22001338757

SAFETY LIMITING VALUES

Symbol	Parameter	Condition	Value	Unit
Is	Safety input, output, or supply current	R _{θJA} =125°C/W, V _{CC} -V _{EE} = 15V, T _J =150°C, T _A =25°C	50	mA
		R _{θJA} =125°C/W, V _{CC} -V _{EE} = 30V, T _J =150°C, T _A =25°C	25	mA
Ps	Safety input, output, or total power	R _θ JA=125°C/W, T _J =150°C, T _A =25°C	750	mW
Ts	Maximum safety temperature		150	°C

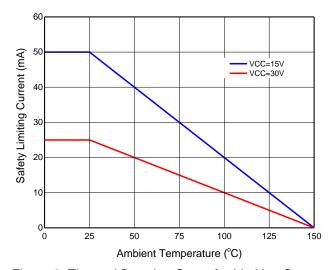


Figure 3. Thermal Derating Curve for Limiting Current per VDE

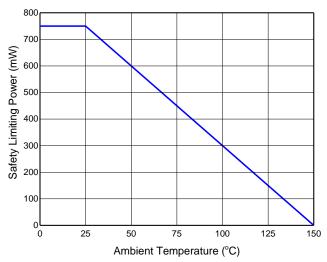


Figure 4. Thermal Derating Curve for Limiting Power per VDE



ELECTRIAL CHARACTERISTICS (DC)

 V_{CC} - V_{EE} = 15V, V_{EE} = GND and T_A = 25°C unless otherwise specified. All min and max specifications are at T_A = -40°C to 125°C

Symbol	Parameter	Condition	Min	Тур	Max	Unit
INPUT						
I _{FLH}	Input Forward Threshold Current Low to High		1.8	2.1	3	mA
VF	Input Forward Voltage	I _F =10mA	2.1	2.25	2.5	V
ΔV _F /ΔΤ	Temp Coefficient of Input Forward Voltage	I _F =10mA		0.5		mV/°C
V _R	Input Reverse Breakdown Voltage	I _R =10uA	30			V
OUTPUT(S	SLM340/SLM345)		l .			
Іон	High Level Peak Output Current	Vcc=15V, I _F =10mA, C _{VDD} =10uF, C _{LOAD} =220nF		1.0		А
l _{OL}	Low Level Peak Output Current	V_{CC} =15V, V_{F} =0V, C_{VDD} =10uF, C_{LOAD} =220nF		1.0		А
Vон	High Level Output Voltage	I _F =10mA, I _O =-20mA "With respect to Vcc"		105		mV
Vol	Low Level Output Voltage	V _F =0V, I _O =20mA		50		mV
OUTPUT(S	SLM341/SLM346)	L	l .	1		
Іон	High Level Peak Output Current	V_{CC} =15V, I_F =10mA, C_{VDD} =10uF, C_{LOAD} =220nF		3.0		А
loL	Low Level Peak Output Current	V_{CC} =15V, V_{F} =0V, C_{VDD} =10uF, C_{LOAD} =220nF		3.0		А
V _{OH}	High Level Output Voltage	I _F =10mA, I _O =-20mA "With respect to Vcc"		26		mV
V _{OL}	Low Level Output Voltage	V _F =0V, I _O =20mA		13		mV
OUTPUT(S	SLM343)		l .			
Іон	High Level Peak Output Current	$\begin{array}{c} V_{\text{CC}}\text{=}15\text{V},I_{\text{F}}\text{=}10\text{mA},\\ C_{\text{VDD}}\text{=}10\text{uF},\\ C_{\text{LOAD}}\text{=}220\text{nF} \end{array}$		4.0		А
l _{OL}	Low Level Peak Output Current	V _{CC} =15V, V _F =0V, C _{VDD} =10uF, C _{LOAD} =220nF		6.0		А
V _{OH}	High Level Output Voltage	I _F =10mA, I _O =-20mA "With respect to Vcc"		26		mV
Vol	Low Level Output Voltage	V _F =0V, I _O =20mA		13		mV



Symbol	Parameter	Condition	Min	Тур	Max	Unit
UNDER VO	DLTAGE LOCKOUT(SLM340/SLM341/SL	M343)				
UVLOR	Under Voltage Lockout Vcc rising	I _F =10mA	11.5	12.5	13.5	V
UVLO _F	Under Voltage Lockout Vcc falling	I _F =10mA	10.5	11.5	12.5	V
UVLO _{HYS}	Under Voltage Lockout Hysteresis			1.0		V
UNDER VO	DLTAGE LOCKOUT (SLM345/SLM346)	l		l		
UVLO _R	Under Voltage Lockout Vcc rising	I _F =10mA	8	8.5	9	V
UVLOF	Under Voltage Lockout Vcc falling	I _F =10mA	7	7.5	8	V
UVLO _{HYS}	Under Voltage Lockout Hysteresis			1.0		V

SWITCHING CHARACTERISTICS (AC)

 V_{CC} - V_{EE} = 15V, V_{EE} = GND and T_A = 25°C unless otherwise specified. All min and max specifications are at T_A = -40°C to 125°C

Symbol	Parameter	Condition	Min	Тур	Max	Unit
tplH	Propagation delay, Low to High			90	120	ns
tphL	Propagation delay, High to Low	C _{LOAD} =1nF, f _{sw} =20kHz,		90	120	ns
t _r	Turn on rise time	(50% Duty Cycle),			25	ns
t _f	Turn off fall time	- V00-10 V			12	ns
t _{PWD}	Pulse Width Distortion				35	ns
t _{PDD}	Propagation Delay Difference Between Any Two Parts				25	ns
tuvlo_rec	UVLO Recovery Delay	Vcc Rising from 0V to 15V		22	30	us
СМТІн	Output High Level Common Mode Transient Immunity	I _F =10mA, V _{CM} =1000V, V _{CC} =15V, T _A =25°C	150	200		kV/us
CMTI∟	Output Low Level Common Mode Transient Immunity	V _F =0V, V _{CM} =1000V, V _{CC} =15V, T _A =25°C	150	200		kV/us



PARAMETER MEASUREMENT INFORMATION

Propagation Delay, Rise Time and Fall Time

Figure 5 shows the propagation delay from the input forward current I_F , to V_{OUT} . This figure also shows the circuit used to measure the rise (t_r) and fall (t_f) times and the propagation delays t_{PDLH} and t_{PDHL} .

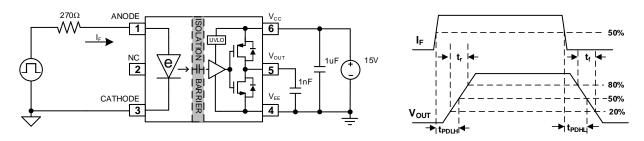


Figure 5. Propagation Delay, Rise Time and Fall Time

IOH and IOL Testing

Figure 6 shows the circuit used to measure the output drive current I_{OL} and I_{OH} . A load capacitance of 220nF is used at the output. The peak dv/dt of the capacitor voltage is measured in order to determine the peak source and sink currents of the gate driver.

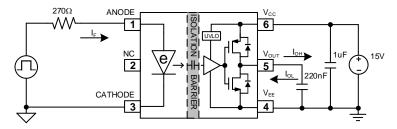


Figure 6. IoH and IoL

CMTI Testing

Figure 7 is the simplified diagram of the CMTI testing. Common mode voltage is set to 1000V. The test is performed with IF=10mA (Vout= High) and VF=0V (Vout= Low).

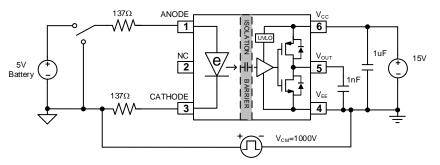


Figure 7. CMTI Test Circuit



FEATURE DESCRIPTION

SLM34x is a single channel isolated gate driver, with an opto-compatible input stage, that can drive IGBTs and MOSFETs. It has 1.0 A to 4.0A peak output current capability with maxim output driver supply voltage of 40V. The inputs and the outputs are galvanically isolated. SLM34x is offered in SOP6W package with >8.5mm creepage and clearance. The reinforced isolation rating is 5kV_{RMS} for 60 seconds. It is pin-to-pin compatible with standard opto-coupler isolated gate drivers use an LED as the input stage, SLM34x uses an emulated diode as the input stage which does not use light emission to transmit signals across the isolation barrier. The input stage is isolated from the driver stage by dual, series HV SiO2 capacitors in full differential configuration that not only provides reinforced isolation but also offers great performance of common mode transient immunity >150kV/us. The e-diode input stage along with capacitive isolation technology gives SLM34x several performance advantages over standard opto-coupler isolated gate drivers.

- Since the emulated diode does not use light emission for its operation, the reliability and aging characteristics of SLM34x are naturally superior to those of standard opto-coupler isolated gate drivers.
- Higher ambient operating temperature range of 125°C, compared to only 105°C for most opto-coupler isolated gate drivers
- The e-diode forward voltage drop has less part-to-part variation and smaller variation across temperature.
 Hence, the operating point of the input stage is more stable and predictable across different parts and operating temperature
- Higher common mode transient immunity than opto-coupler isolated gate drivers
- Smaller propagation delay than opto-coupler isolated gate drivers
- Due to superior process controls achievable in capacitive isolation compared to opto-coupler isolation, there is less part-to-part skew in the propagation delay, making the system design simpler and more robust
- Smaller pulse width distortion than opto-coupler isolated gate drivers

Input Stage

The input stage of SLM34x is an emulated diode. When the emulated diode is forward biased by applying a positive voltage to the Anode with respect to the Cathode, a forward current, I_F, flows into the e-diode. The forward voltage drop across the e-diode is 2.25V (typ). An external resistor should be used to limit the forward current. The recommended range for the forward current is 7mA to 16mA. When I_F exceeds the input forward threshold current I_{FLH} (2.1mA typ), the V_{OUT} is driver high. If the I_F is lower than I_{FLH}, or the voltage between Anode and Cathode is reverse biased, the V_{OUT} is driven low.

The reverse breakdown voltage of the e-diode is up to 30V. The large reverse breakdown voltage of the e-diode enables SLM34x to be operated in interlock architecture as shown in Figure 8. The example shows two gate drivers driving a set of IGBTs. The inputs of the gate drivers are connected as shown in Figure 8 and driven by two buffers that are controlled by the MCU. Interlock architecture prevents both the e-diodes from being "ON" at the same time, preventing shoot through in the IGBTs as shown in Figure 9. It also ensures that if both PWM signals are erroneously stuck high (or low) simultaneously, both gate driver outputs will be driven low.

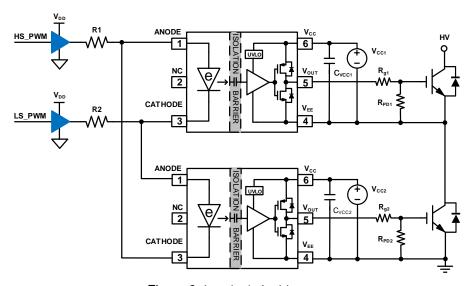
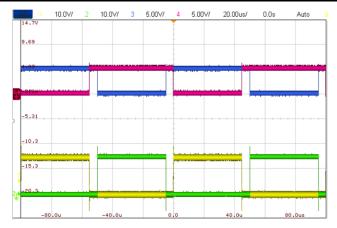


Figure 8. Interlock Architecture





CH1: HS_OUT, CH2: LS_OUT, CH3: HS_PWM, CH4: LS_PWM

Figure 9. Interlock PWM input and output waveform

Under Voltage Lockout (UVLO)

The SLM34x integrates the UVLO protection on the V_{CC} to prevent an under driven condition on IGBTs and MOSFETs. When V_{CC} is lower than UVLO_R during start up or lower than UVLO_F after start up, the UVLO feature holds the V_{OUT} low, regardless of the input forward current. A hysteresis on the UVLO feature prevents glitch when there is noise from the power supply. When V_{CC} drops below UVLO_F, a recovery delay (t_{UVLO_REC}) occurs on the output when the supply voltage rises above UVLO_R again.

Typical Input Configuration Circuit

The circuit in Figure 10 and Figure 11 show two typical input configuration circuits for SLM34x to driver IGBT.

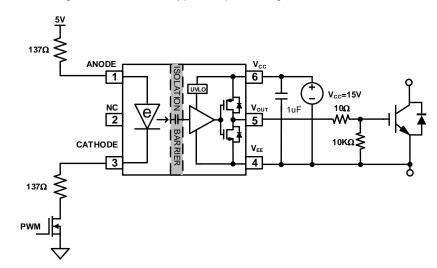


Figure 10. Single MOSFET Circuit as Input Drive of SLM34x to Drive IGBT

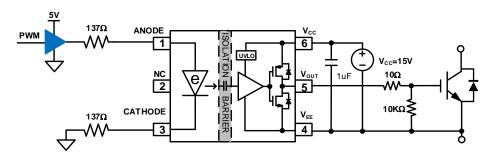


Figure 11. Buffer Circuit as Input Drive of SLM34x to Drive IGBT



Layout

In order to achieve optimum performance for the SLM34x, some suggestions on PCB layout.

Component placement:

- Low ESR and low ESL capacitors must be connected close to the device between the V_{CC} and V_{EE} pins to bypass noise and to support high peak currents when turning on the external power transistor.
- To avoid large negative transients on the VEE pins connected to the switch node, the parasitic inductances between the source of the top transistor and the source of the bottom transistor must be minimized.

Grounding considerations:

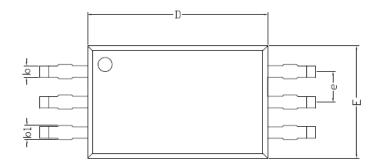
• Limiting the high peak currents that charge and discharge the transistor gates to a minimal physical area is essential. This limitation decreases the loop inductance and minimizes noise on the gate terminals of the transistors. The gate driver must be placed as close as possible to the transistors.

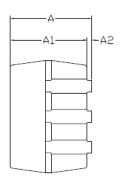
High-voltage considerations:

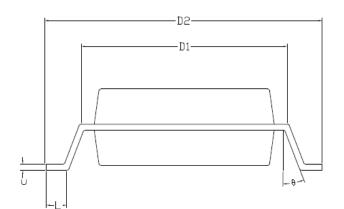
 To ensure isolation performance between the primary and secondary side, avoid placing any PCB traces or copper below the driver device. A PCB cutout or groove is recommended in order to prevent contamination that may compromise the isolation performance.



PACKAGE CASE OUTLINES





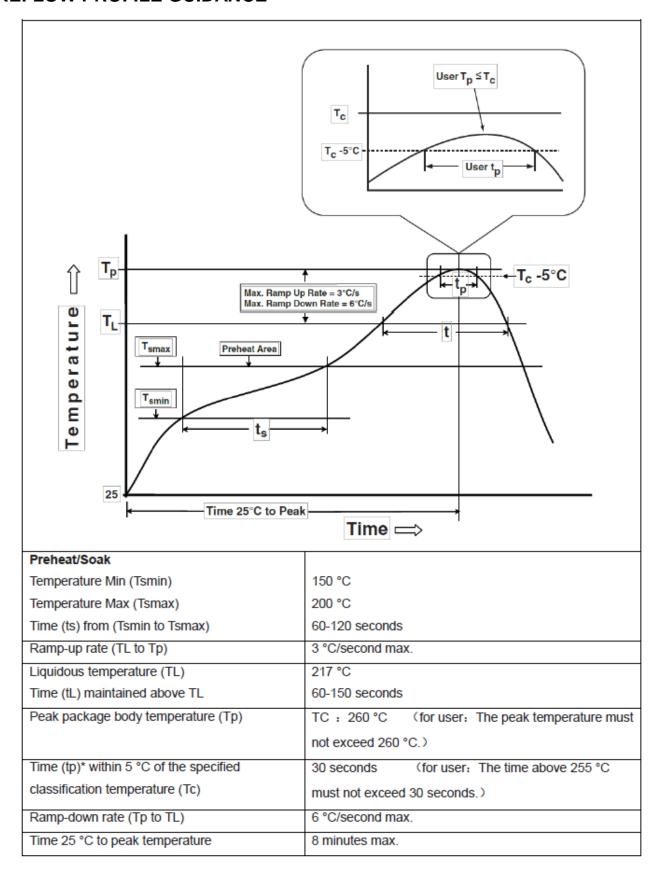


Dimension	MIN	NOM	MAX		
A	3. 2	3.4	3.6		
A1	3	3. 2	3.4		
A2	0.1	-	0.3		
b	0.35	0.4	0.45		
b1	0.45	0.48	0.51		
С	0.2	0. 25	0.33		
D	7.4	7. 5	7.6		
D1	8.62	8. 72	8.82		
D2	11.25	11.5	11.75		
Е	4.58	4.68	4.78		
е	1. 27 BSC				
L	0.5	0.75	1		
θ		23° REF			
	Unit	· mm			

Figure 12. SOP6W Package Outline Dimensions



REFLOW PROFILE GUIDANCE





REVISION HISTORY

Note: page numbers for previous revisions may differ from page numbers in current version

Subjects (major changes since previous revision)	
22-1-5	
Initial release	
22-3-25	
Add thermal information	
Add the test condition in the Insulation specifications	
Add safety related certifications	
Add safety limiting values	
22-9-25	
Update the specification values in the insulation specifications	
Update the VDE certification file number	
	Initial release 22-3-25 Add thermal information Add the test condition in the Insulation specifications Add safety related certifications Add safety limiting values 22-9-25 Update the specification values in the insulation specifications